Information Criterion

Ways to quantify error in a given estimator.

One idea

$$\overline{err} = \mathbb{E}_{\gamma} \left[\frac{1}{n} \sum_{i=1}^{n} L(y_i, \hat{f}(z_i)) \right]$$

In general under etimates error due to training and testing on [X].

Create a new dataset of responses $Y_i^{(new)}$ to get a better estimate :

of the error $\text{Errin} = \text{Ery} \left[\frac{1}{N} \sum_{i=1}^{N} L(\hat{S}(x_i), Y_i) \right]$

View Yill as R.U. coming from the underlying model.

Def: The difference between the training error and the theoretical error is given by the optimisism

and the true optimism is given by

$$\mathbb{E}_{\tau}\left[o_{\vec{p}}\right] = \frac{2}{N} \sum_{i=1}^{N} \operatorname{Cov}\left(\hat{y}_{i}, y_{i}\right)$$

Which fields
$$E_{\tau}[E_{rin}] = \overline{err} + \frac{2}{N} \sum_{i=1}^{\infty} Cos(Y_i, \hat{Y}_i)$$

We normally say # = (Frein) is the CP information criterion.

VC Dimension Criterian

Rmk: Optimism related to how complex the space fo F.

Suppose f(x) = IA (classification) e.g. H=[x: ptx=0]

Def: The family F of indicater functions is suid to <u>shatter</u> a collection of points $C \subseteq F$. If for every subset $C_1 \subseteq C$. then exists

Def: I has UC dimension if it can shather any collection of points

Thm: $\mathbb{E}\left[L\left(\hat{f}(X,Y)\right)\right] = \mathbb{E}_{r_{\tau}} \leq \frac{\mathbb{E}_{r_{\tau}}}{(1-r_{\tau})_{+}} \qquad \mathcal{E} = h\left(\log \frac{N_{1}+1}{1-\log n_{1}}\right) - \log \frac{n}{4}$

h = VC dimension with probability 1-M.

Bootstrapping

Define == (x,T y) with a goal of estimating S(Z).

Estimate the density p and resumple from it to estimate

(S(Z));=1